Dangelmayer

### 2012 ESD Workshop July 24, 25, 26, & 27

#### **Beyond S2020: Class 0 Best Practices**

&

Advanced ESD Measurements

New Topics, Two Invited Speakers, and 4th Day!

(CDM = Charged Device Model; Class 0= Ultra-Sensitive Components: EOS = Electrical Overstress)

ESD Dream Team www.dangelmayer.com













Dave Long - Staticworx "ESD Flooring Safety and Walking Voltage Test Methods for S20.20"

Mark Hogsett – Simco-Ion "A Process Monitoring Breakthrough In-Situ CDM Event Simulation (New Technology)"

Hands-on ESD Workshop with the Dream Team: Basic and Advanced Principles

**Intended For Professionals Who:** 

- Have Achieved Basic Knowledge Of ESD
- Desire Roadmap For Today's Advanced Technologies
- Need A Better Understanding of CDM, CBE, Class 0, and S20.20

What You Will Learn:

- The Latest ESD Trends
- Class 0 Fundamentals & Advanced Concepts
- CDM, CBE & Class 0 Counter Measures
- Hands-On CDM & Class 0 Test Methods
- Auditing Skills & Class Exercises
- 99.9% of ESD Failures are CDM Not HBM or MM
- Most FA Experts Misdiagnose CBE as EOS
- How to Implement Sound ESD S20.20 Programs
- Class 0 Advanced Measurement Techniques

# Workshop Agenda

8:00	Day 1: Tuesday, July 24, 2012 Introductions – Beyond S20.20	
AM	<ul> <li>The Latest ESD Trends – Wafers, Devices, Boards, &amp; Systems – <u>Terry Welsher</u></li> <li>Break</li> </ul>	Ted
	<ul> <li>ESD Basics – <u>Terry Welsher &amp; Ted Dangelmayer</u></li> <li>With Emphasis on CDM &amp; Class 0</li> <li>Why CDM &amp; Class 0 are Not Well Understood</li> </ul>	Dangelmayer President
	<ul> <li>CDM vs. HBM</li> <li>Discharge Characteristics</li> <li>Limitations of Designed-in-Protection</li> <li>Why MM Unnecessary</li> <li>Demonstrations and Videos</li> </ul>	Terry
12:00	<ul> <li>FMA: Differentiation Among the 3 Models</li> <li>Lunch</li> </ul>	Welsher Sr. Vice
PM	• ESD Basics (Continued)	President
	• Break	
5.00	• ESD Basics (Continued)	
5:00 5:30	• Adjourn	- A P
5:30	Evening: Complimentary Seaside Dinner	Larry Fromm Director

## Workshop Agenda

	D	ay 2: Wednesday, July 27, 2011	
8:00	0	Auditing Measurement Pitfalls	
		- <u>Ginger Hansel</u>	
AM		<ul> <li>Common Measurement Pitfalls</li> </ul>	2 A
		<ul> <li>Field Meters</li> </ul>	
		<ul> <li>Voltmeters</li> </ul>	
		<ul> <li>Resistance Meters</li> </ul>	
		<ul> <li>Event Detectors</li> </ul>	Ginger
	0	Hands-on – Class Exercises	Hansel
		<ul> <li>Resistance Measurements</li> </ul>	Director
		<ul> <li>Event Detection</li> </ul>	
	0	Break	
		• Invited Speaker: Dave Long – Staticworx	
		"ESD Flooring Safety & Walking Voltage Test Methods	100
		for S20.20"	A CONTRACTOR
12:00	0	Lunch – Annisquam Yacht Club	
	0	ESDA TR53 Test Methods & Troubleshooting	
PM		– <u>Carl Newberg</u>	Carl
		<ul> <li>Grounding / Bonding Systems</li> </ul>	Newberg
		• Worksurfaces	Director
		<ul> <li>Wrist Straps</li> </ul>	
		<ul> <li>Constant Monitors</li> </ul>	
		• Footwear	
		• Flooring	
		• Personnel Grounding with Garment	
		o Garments	
		• Air Ionizers	
		o Seating	
		<ul> <li>Mobile Equipment (Carts)</li> </ul>	
		• Packaging	
	0	Break	
	0	<b>CDM Compliance Verification</b> – <u><i>Ted Dangelmayer</i></u>	
		• Common Findings	
		• Personnel Compliance	
5:00	0	Adjourn	
6:30	0	Sunset River Cruse	

# Workshop Agenda

8:00	Day 3: Thursday, July 26, 2012 <ul> <li>Ionization for Class 0 – Arnie Steinman</li> <li>Class 0 Considerations</li> </ul>	
AM	<ul> <li>Ionizer Choices vs. Applications</li> <li>Hands-on – Class Exercises <ul> <li>Fieldmeter vs. Voltmeter</li> <li>Ionizers</li> </ul> </li> <li>Break</li> </ul>	
12:00	<ul> <li>Advancements in CBE (Charged Board Event) &amp; CDE (Cable Discharge Event) – Terry Welsher</li> <li>Lunch</li> </ul>	Arnie Steinman
PM	How Do You Know Your Program is Working? – Arnie Steinman	Director
	<ul> <li>ESD Programs for a Lab Environment – Ted Dangelmayer</li> <li>Break</li> </ul>	
	<b>Packaging S541 Standard Review - Pros and Cons – Ginger</b> Hansel – Carl Newberg Dollar Impact of Overkill Shielding- Clamshell Testing	
5:00	Open Discussion <ul> <li>Adjourn</li> </ul>	

### Latest Advances in ESD Event Measurements Including Class 0 Applications

	Day 4: Friday, July 27, 2012	
8:00	<b>Overview - Advanced Measurements – Terry Welsher</b>	
	• Current Probe	
	• Contact Voltmeter	
	• Event Detection – Antenna Comparisons	
	<ul> <li>Oscilloscope vs. Detectors</li> </ul>	
	• Standards Overview	
	Process Assessments	
	<ul> <li>Handler Measurements</li> </ul>	
	• Gemini Observatory Class 000 Case Study	0
	CCD Handling & Installation	IST .
	0	
	<b>Correlating Event Amplitudes with Device Sensitivity –</b>	
	Terry Welsher	17/
	Break	Terry
		Welsher
	Invited Speaker - Mark Hogsett of Simco-Ion	Sr. Vice
	"A Process Monitoring Breakthrough	President
	In-Situ CDM Event Simulation (New Technology)"-	
12:00	Lunch	
	Hands-on – Class Exercises	
PM	<b>Oscilloscope Current Probe Measurements</b>	
	Contact Voltmeter Measurements	
	<b>Event Detection – compare to advanced equipment</b>	
	• • • •	
	Break	
	Class 00 (Sub 125V Controls) - <u>Carl Newberg – update with</u>	
	IEW seminar	
	Ultra-Sensitive Device/Board Controls	
	<b>Avoiding High Failure Rates (up to 100%)</b>	
	Open Discussion	
	Adjourn	
5:00		

Location: C	Cape Ann,	<b>Gloucester</b> , MA
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America's 1<sup>st</sup> Fishing Port & Frequent Movie Venue



Location: Cape Ann, Gloucester, MA

Local Sightseeing and Accommodations: <u>www.cape-ann.com</u>

Major hotels w/i 30 minutes of Gloucester:Peabody Marriott978-977-9700Comfort Inn, Peabody978-777-1700Courtyard Marriott, Danvers978-777-8630

Transportation 45 minute drive from Boston's Logan airport 55 minute train ride from Boston 1.25 hr. drive from Manchester, NH airport



Vicki Dangelmayer

Vice President of Business Development

#### Abstract: **A Process Monitoring Breakthrough** In-Situ CDM Event Simulation (New Technology)

By Mark Hogsett – Simco-Ion

The Simco-Ion CDM Event Simulator was co-designed with Intel to allow ESD detectors to be calibrated inside the tools and processes where CDM events occur. This simulation tool allows calibrated CDM events of different magnitudes to be produced at the point where production devices are most vulnerable and where ESD monitoring sensors are located. This approach allows the highest level of handling safety for sensitive devices.

Devices are usually characterized for failure thresholds in formal test beds and machines designed to simulate discharges on the various device input and output connections. This information is used to assess baseline risk during all phases of device manufacture and system integration. Using this device failure threshold information in conjunction with the CDM Event Simulator, the manufacturing process itself can be calibrated to the CDM risk model.

Many applications in semiconductor, disk-drive, FPD, automated IC handling and a host of other manufacturing processes handle sensitive product in locations where direct discharges can occur. Simulating CDM events at the point of monitoring has posed challenges when attempting to use actual charged devices. Part of this difficulty concerns repeatability of the discharge events themselves. Other difficulties exist due to conditions imposed upon the radiated waveform by the materials and configuration of the process point itself. The CDM Event Simulator was developed to alleviate these problems by providing a repeatable CDM calibration event at the process point which takes into account uncharacterized location conditions.



(CDM = Charged Device Model; Class 0= Ultra-Sensitive Components: EOS = Electrical Overstress) 14 Butternut Lane, Gloucester, MA 01930

#### **REGISTRATION FORM**

Workshop includes continental br	reakfast and lunch eacl	h day, and dinner on Day 1.		
Please select one fee:				
For Days 1, 2, 3: \$1,785	For Days 1, 2, 3: \$1,785 per person. Register by June 30, 2012 for \$1,635			
For Days 1, 2, 3, 4: \$2,380	For Days 1, 2, 3, 4: \$2,380 per person. Register by June 30, 2012 for \$2,180			
<b>Registration Information</b>		•		
Name:	Title:			
Company:				
Mail Stop:				
Address:				
City:	State:	Zip:		
		-		
E-mail:		Fax:		
Preferred method of contact: Phot	ne E-mail:	Fax:		
Credit CardVisaMaster C Card # Billing Address Name on Card	Expiration Date	Security Code		
Please make check payable to: Dangelmayer Associate Mail to: 14 Butternut Lane Gloucester, MA 01930	es	lations, go to www. cape-ann.com Peabody Marriott 978-977-9700 Comfort Inn 978-777-1700 Marriott Courtyard 978-777-8630		
Thank you! Vicki Dangelmayer	Co	Seating is limited! omplete your registration today!		
Vice President of Sales vicki@dangelmayer.com				

Contact: Vicki Dangelmayer; <u>vicki@dangelmayer.com</u>; 978-283-5156 Detach and retain for your records

2012 ESD Dream Team Workshop: Days 1, 2, 3: \$1,785.00 (\$1,635.00 by June 30, 2012) Days 1, 2, 3, 4: \$2,380 per person. (\$2,180.00 by June 30, 2012)

Date paid: \_\_\_\_\_ Check #: \_\_\_\_\_ Amount: \_\_\_\_\_

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